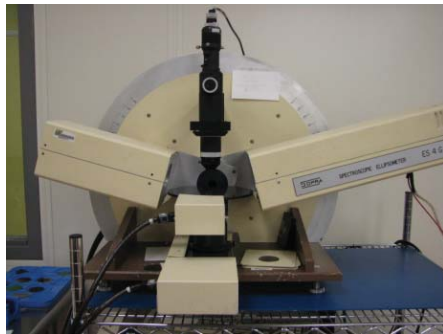


Non-contact nanometer scale measurements for film thickness, Index of refraction



**Sopra ES4G Ellipsometer**

- 0.1nm resolution
- Spectroscopic
- Up to 5 layers
- Refractive index



**Rudolph Auto ELIII  
Null Ellipsometer**

- 0.1nm Resolution
- Up to 2 layers
- Refractive index



**Nanospec 210  
Reflectometer**

- 50nm-10um range
- 5x, 10x, 100x
- Microspot measurement



**Filmetrics F20  
Reflectometer**

- 50nm-50um range
- Up to 5 layers
- Fast measurement



**Wyko 9100NT**

- Non-Contact
- 10mm max height
- nm scale resolution
- Automated stage